



TEST REPORT

REPORT NO.KA/2004/50448
DATE: 2004/6/1
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THE FOLLOWING MERCHANDISE WAS(WERE) SUBMITTED AND IDENTIFIED BY THE CLIENT AS :

CLIENT : ADVANCED SEMICONDUCTOR ENGINEERING INC..
PRODUCT DESCRIPTION : IC COMPONENT PACKAGE.
PACKAGE TYPE : LEAD FINISH(Pure Tin).
TESTING DATE : 2004/5/26 TO 2004/6/1 .
SAMPLE RECEIVED : 2004/05/25.

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WE HAVE TESTED THE SAMPLE(S) SUBMITTED AS REQUESTED AND THE FOLLOWING RESULTS WERE OBTAINED.

TEST ITEM(S)	UNIT	METHOD	DET. LMT	RESULT
CADMIUM	ppm	ANALYSIS BY ICP-AES WITH ADVANCE TREATMENT EN1122, METHOD B:2001.	2	n.d.
CHROMIUM VI	ppm	ANALYSIS BY US EPA 7196A WITH ADVANCE TREATMENT US EPA 3060A.	2	n.d.
MERCURY	ppm	ANALYSIS BY ICP-AES WITH ADVANCE TREATMENT US EPA 3052	2	n.d.
LEAD	ppm	ANALYSIS BY ICP-AES WITH ADVANCE TREATMENT US EPA 3050B	2	28.6

NOTE : n.d. = not detected.

<END>



**George Huang / Supervisor
Sign for and on behalf of
SGS Taiwan Limited**

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